

OptiMOS[™]2 Small-Signal-Transistor

Features

- N-channel
- Enhancement mode
- Logic level (4.5V rated)
- · Avalanche rated
- Qualified according to AEC Q101
- 100%lead-free; RoHS compliant
- Halogen-free according to IEC61249-2-21

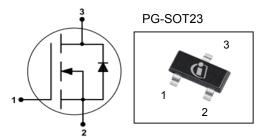






Product Summary

V _{DS}		30	V
$R_{\rm DS(on),max}$ $V_{\rm GS}$ =10 V		160	mΩ
	V _{GS} =4.5 V	280	
I _D	1.4	Α	



Туре	Package	Tape and Reel Information	Marking	Lead Free	Packing
BSS316N	SOT23	H6327: 3000 pcs/ reel	SYs	Yes	Non dry

Maximum ratings, at T_j =25 °C, unless otherwise specified

Parameter	Symbol	Conditions	Value	Unit
Continuous drain current	ID	T _A =25 °C	1.4	А
		T _A =70 °C	1.1	1
Pulsed drain current	I _{D,pulse}	T _A =25 °C	5.6	
Avalanche energy, single pulse	E _{AS}	/ _D =1.4 A, R _{GS} =25 Ω	3.7	mJ
Reverse diode dv/dt	dv/dt	/ _D =1.4 A, V _{DS} =16 V, d <i>i</i> /d <i>t</i> =200 A/μs, T _{j,max} =150 °C	6	kV/µs
Gate source voltage	V_{GS}		±20	V
Power dissipation	P_{tot}	T _A =25 °C	0.5	W
Operating and storage temperature	$T_{\rm j},T_{\rm stg}$		-55 150	°C
ESD Class		JESD22-A114 -HBM	0 (<250V)	1
Soldering Temperature			260 °C	
IEC climatic category; DIN IEC 68-1			55/150/56	



Parameter	Symbol	Conditions	Values		Unit	
			min.	typ.	max.	
Thermal characteristics						
Thermal resistance, junction - ambient	$R_{ ext{thJA}}$	minimal footprint 1)	-	-	250	K/W

Electrical characteristics, at $T_{\rm j}$ =25 °C, unless otherwise specified

Static characteristics

Drain-source breakdown voltage	V _{(BR)DSS}	V _{GS} =0 V, I _D =250 μA	30	-	-	V
Gate threshold voltage	$V_{\rm GS(th)}$	$V_{\rm DS}$ = $V_{\rm GS}$, $I_{\rm D}$ =3.7 μA	1.2	1.6	2.0	
Drain-source leakage current	I _{DSS}	$V_{\rm DS}$ =30 V, $V_{\rm GS}$ =0 V, $T_{\rm j}$ =25 °C	1	1	1	μΑ
		V _{DS} =30 V, V _{GS} =0 V, T _j =150 °C	-	-	100	
Gate-source leakage current	I _{GSS}	V _{GS} =30 V, V _{DS} =0 V	-	-	100	nA
Drain-source on-state resistance	$R_{DS(on)}$	V _{GS} =4.5 V, I _D =1.1 A	-	191	280	mΩ
		V _{GS} =10 V, I _D =1.4 A	-	119	160	
Transconductance	g fs	V _{DS} >2 I _D R _{DS(on)max} , I _D =1.1 A		2.3		S

 $^{^{1)}}$ Performed on 40mm^2 FR4 PCB. The traces are 1mm wide, $70\mu\text{m}$ thick and 20mm long; they are present on both sides of the PCB.

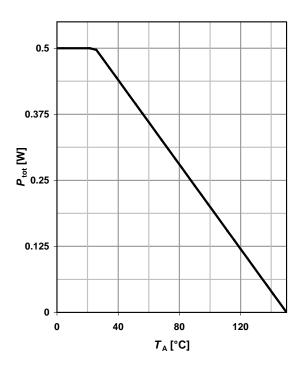


Parameter	Symbol	Symbol Conditions		Values		Unit
			min.	typ.	max.	
Dynamic characteristics						
Input capacitance	Ciss		-	71	94	pF
Output capacitance	Coss	V _{GS} =0 V, V _{DS} =15 V, f=1 MHz	-	26	35	
Reverse transfer capacitance	C _{rss}		-	5	7	
Turn-on delay time	t _{d(on)}		-	3.4	-	ns
Rise time	t _r	V _{DD} =15 V, V _{GS} =10 V,	-	2.3	-	
Turn-off delay time	$t_{d(off)}$	$I_{\rm D}$ =1.4 A, $R_{\rm G}$ =6 Ω	-	5.8	-	
Fall time	t_{f}	1	-	1	-	
Gate Charge Characteristics		T		Г	Π	
Gate to source charge	Q _{gs}		-	0.3	-	nC
Gate to drain charge	Q _{gd}	V _{DD} =15 V, I _D =1.4 A,	-	0.2	-	
Gate charge total	Q_g	$V_{\rm GS}$ =0 to 5 V	-	0.6	-	
Gate plateau voltage	$V_{\rm plateau}$		-	3.4	-	٧
Reverse Diode						
Diode continous forward current	Is	- T _A =25 °C	-	-	0.5	А
Diode pulse current	I _{S,pulse}	7 A-25 C	-		5.6	
Diode forward voltage	V _{SD}	V _{GS} =0 V, I _F =1.4 A, T _j =25 °C	-	0.8	1.1	V
Reverse recovery time	t _{rr}	V _R =10 V, I _F =1.4 A,	-	9.1	-	ns
Reverse recovery charge	Q _{rr}	d <i>i_F</i> /d <i>t</i> =100 A/µs	-	2.6	-	nC

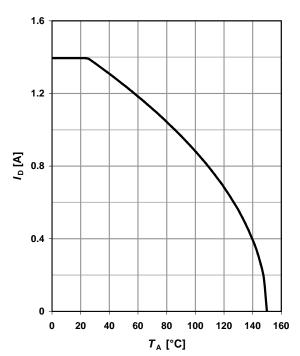


1 Power dissipation

P_{tot} =f(T_A)



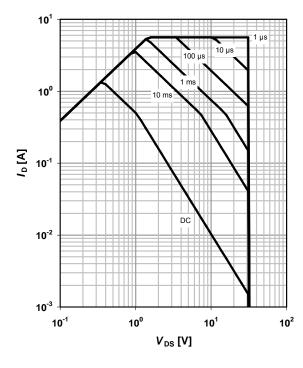
2 Drain current



3 Safe operating area

$$I_{\rm D}$$
=f($V_{\rm DS}$); $T_{\rm A}$ =25 °C; D =0

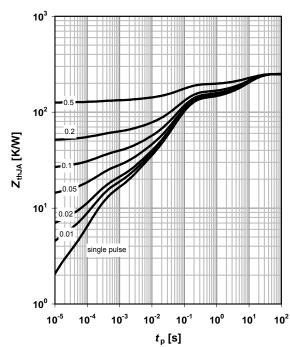
parameter: $t_{\rm p}$



4 Max. transient thermal impedance

$$Z_{\rm thJA}$$
=f($t_{\rm p}$)

parameter: $D=t_p/T$

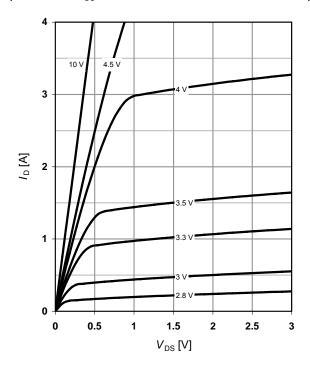




5 Typ. output characteristics

 $I_D = f(V_{DS}); T_j = 25 °C$

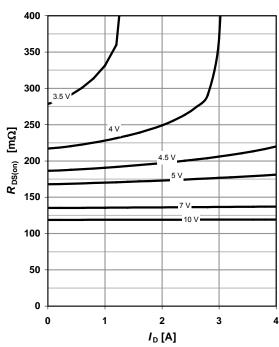
parameter: $V_{\rm GS}$



6 Typ. drain-source on resistance

 $R_{DS(on)}$ =f(I_D); T_j =25 °C

parameter: V_{GS}

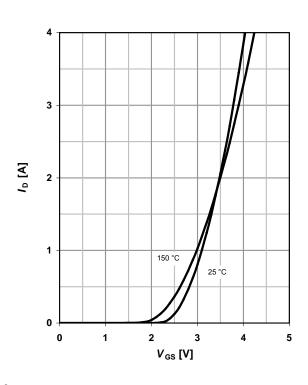


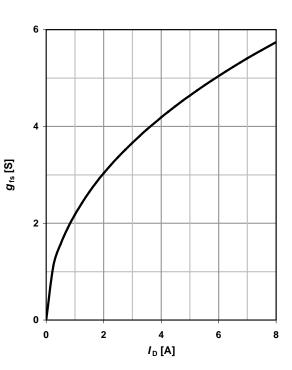
7 Typ. transfer characteristics

 I_{D} =f(V_{GS}); $|V_{DS}|$ >2 $|I_{D}|R_{DS(on)max}$

8 Typ. forward transconductance

 g_{fs} =f(I_D); T_j =25 °C

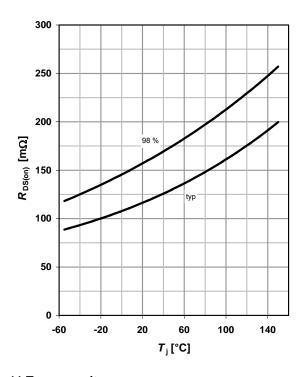






9 Drain-source on-state resistance

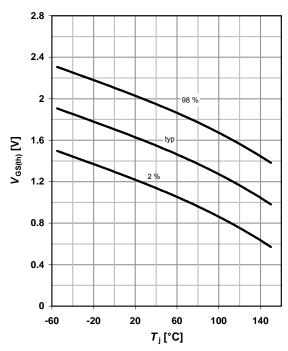
$$R_{DS(on)}$$
=f(T_j); I_D =1.4 A; V_{GS} =10 V



10 Typ. gate threshold voltage

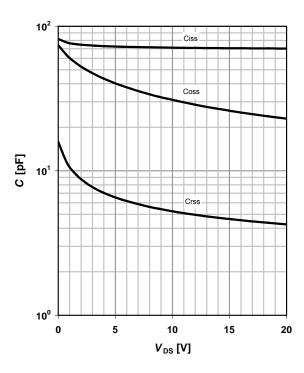
$$V_{\mathrm{GS(th)}}$$
=f(T_{j}); V_{DS} = V_{GS} ; I_{D} =3.7 $\mu\mathrm{A}$

parameter: I_D



11 Typ. capacitances

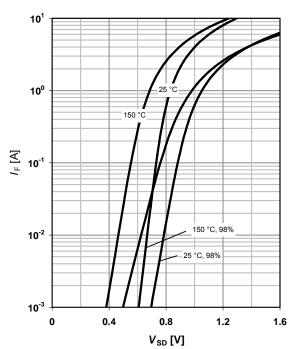
 $C=f(V_{DS}); V_{GS}=0 V; f=1 MHz; T_j=25$ °C



12 Forward characteristics of reverse diode

$$I_{\mathsf{F}} = \mathsf{f}(V_{\mathsf{SD}})$$

parameter: $T_{\rm j}$

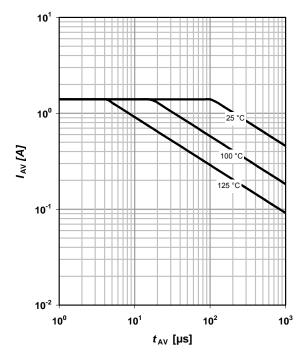




13 Avalanche characteristics

 I_{AS} =f(t_{AV}); R_{GS} =25 Ω

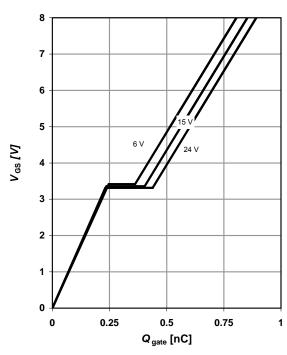
parameter: $T_{j(start)}$



14 Typ. gate charge

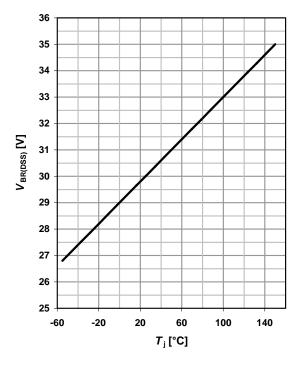
 $V_{\rm GS}$ =f(Q_{gate}); $I_{\rm D}$ =1.4 A pulsed

parameter: $V_{\rm DD}$

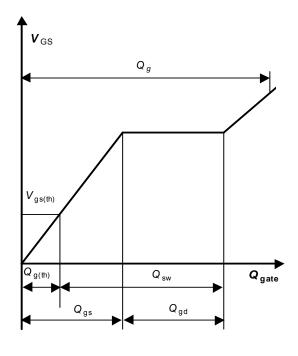


15 Drain-source breakdown voltage

 $V_{BR(DSS)}$ =f(T_i); I_D =250 μ A



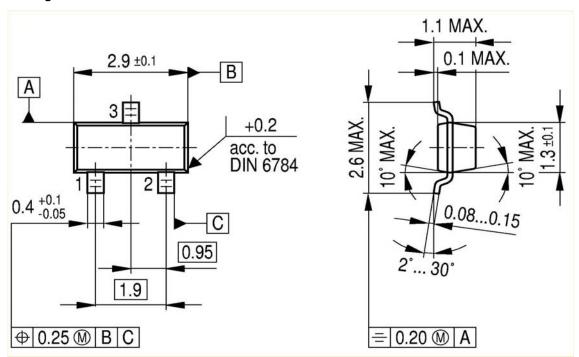
16 Gate charge waveforms



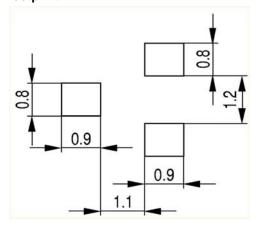


SOT23

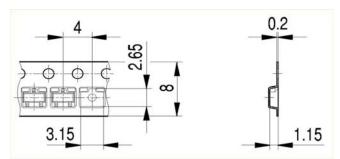
Package Outline:



Footprint:



Packaging:



Dimensions in mm



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